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10/528894

<b>TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR § 1.97(b), 1.97(c), or 1.97(d)</b>		U.S. Patent No. 2001B101B	
<b>In Re Application of: Robert L. LONG et al.</b>			
U.S. Serial No. <b>10/528,894</b>	I.A. Filing Date <b>May 8, 2003</b>	Examiner <b>Not Yet Assigned</b>	Group Art Unit <b>Not Yet Assigned</b>

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Commissioner for Patents  
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**37 CFR § 1.97(b)**

- ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing date of a national application other than a continued prosecution application under § 1.53(d); within three months of the date of entry of the national stage as set forth in § 1.491 in an international application; before the mailing of a first Office Action on the merits; or before the mailing of a first Office Action after the filing of a request for continued examination under § 1.114.

**37 CFR § 1.97(c)**

- ☐ The Information Disclosure Statement submitted herewith is being filed after three months of the filing date of a national application other than a continued prosecution application under § 1.53(d); after three months of the date of entry of the national stage as set forth in § 1.491 in an international application; after the mailing of a first Office Action on the merits; or after the mailing of a first Office Action after the filing of a request for continued examination under § 1.114, but before the mailing date of:

1. a Final Action under § 1.113,
2. a Notice of Allowance under § 1.311, or
3. an action that otherwise closes prosecution in the application,

and is accompanied by either:

- ☐ the fee as set forth in § 1.17(p), or
- ☐ the following statement under § 1.97(e)(1): each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

**37 CFR § 1.97(d)**

- ☐ The Information Disclosure Statement submitted herewith is being filed after a Final Action under § 1.113, a Notice of Allowance under § 1.311, or an action that otherwise closes prosecution in the application, but before, or simultaneously with, the payment of the issue fee. Submitted herewith is the fee as set forth in § 1.17(p) and the following statement under 37 CFR § 1.97(e)(1): each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Applicant hereby request consideration of the Information Disclosure Statement, USPTO form 1449, submitted herewith.

☒ Legible copies of references are enclosed where necessary.

☐ This application is a:  
☐ Continuation / Divisional,  
☐ Continuation-in-Part,

of U.S.S.N. \_\_\_\_\_. Copies of the cited references are ☐ enclosed, where necessary; ☐ not enclosed. References are available in the parent application(s) if not enclosed.

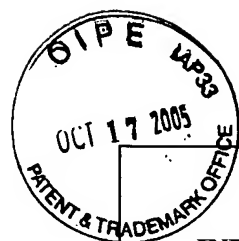
The Commissioner is hereby authorized to charge any additional fees which may be required by this paper, or credit any overpayment, to Deposit Account Number 05-1712. A duplicate copy of this form is enclosed.

October 17, 2005

Date



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## INFORMATION DISCLOSURE STATEMENT

*(Use several sheets if necessary)*

ATTY. DOCKET NO.

2001B101B

SERIAL NO.

10/528,894

APPLICANT

Robert L. LONG et al.

FILING DATE

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GROUP

Not Yet Assigned

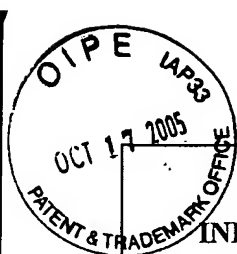
## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	3,725,378	04/03/1973	Chamberlin			
	AB	3,779,712	12/18/1973	Calvert et al.			
	AC	4,175,169	11/20/1979	Beals et al.			
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EXAMINER

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\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant



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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AK	EP 238 796	30.09.87	Europe				
	AL	EP 406 805	13.12.95	Europe				
	AM	EP 561 78 B1	23.04.97	Europe				
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	AO	WO 94/21962	29.09.94	PCT				
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	AR	WO 99/01750	14.01.99	PCT				
	AS	WO 01/09201	08.02.01	PCT				
	AT	WO 01/09203	08/02/01	PCT				

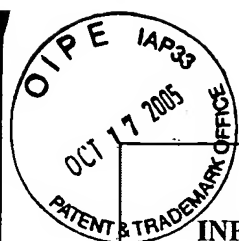
## OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)

	AU	K.R. Beebe et al., "An Introduction to Multivariate Calibration and Analysis," Analytical Chemistry, Vol. 59, No. 17, pp.1007A-1017A, Sept. 1, 1987.
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## OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)

AA	P. Erlich et al., " <u>Fundamentals of the Free-Radical Polymerization of Ethylene</u> ," Advanced Polymer Science, Vol. 7, pp. 386-448, 1970.
AB	M.L. Myrick et al., " <u>In Situ Fiber-Optic Raman Spectroscopy of Organic Chemistry in a Supercritical Water Reactor</u> ," Journal of Raman Spectroscopy, Vol. 25, pp. 59-65, 1994.
AC	T. Naes et al., " <u>Locally Weighted Regression and Scatter Correction for Near-Infrared Reflectance Data</u> ," Analytical Chemistry, Vol. 62, pp. 664-673, 1990.
AD	G.G. Ardell et al., " <u>Model Prediction for Reactor Control</u> ," Chemical Engineering Progress, American Institute of Chemical Engineers, Vol. 79, No. 6, pp. 77-83, June 1, 1983.
AE	J.J. Zacca et al., " <u>Modelling of the Liquid Phase Polymerization of Olefins in Loop reactors</u> ," Chemical Engineering Science, Vol. 48, No. 22, pp. 3743-3765, 1993.
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AL	D.R. Battiste et al., " <u>On-Line Raman Analysis of Ethylene and Hexene in the Phillips 1-Hexene and Polyethylene Processes</u> ," Gulf Coast Conference presentation (Abstract)
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AQ	I. Modric et al., " <u>Raman- und Infrarotspektren isotaktischer Polyalkylathylene*</u> ," Colloid & Polymer Sci., Vol. 254, pp. 342-347, 1976.
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AU	K.P.J. Williams et al., " <u>Use of Micro Raman Spectroscopy for the Quantitative Determination of Polyethylene Density Using Partial Least-Squares Calibration</u> ," Journal of Raman Spectroscopy, Vol. 26, pp. 427-433, 1995.

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